

# Search Notes



Application/Control No.

10/817,196

Examiner

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Applicant(s)/Patent under Reexamination

JAIN ET AL.

Art Unit

2681

## SEARCHED

Class	Subclass	Date	Examiner
455	411	10/14/05	DN
370	338		
455	435-1		
340	5.21		
340	5.74		
380	242		
380	200	10/14/05	DN

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
East search	10/14/05	DN
Search note	10/14/05	DN